

<b>Notice of References Cited</b>	Application/Control No. 10/761,842	Applicant(s)/Patent Under Reexamination YUEH ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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	K	US-			
	L	US-			
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**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 10-39500	02-1998	Japan	Roger et al.	N/A
	O					
	P					
	Q					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	JPO English abstract for JP 10-39500.
	V	English translation for JP 10-39500.
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